

VQ2001 SERIES

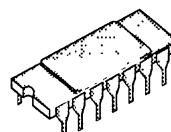
Siliconix
incorporated

P-Channel Enhancement-Mode MOS Transistor
Arrays

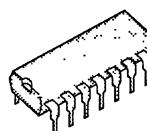
PRODUCT SUMMARY

PART NUMBER	V _{(BR)DSS} (V)	r _{DS(ON)} (Ω)	I _D (A)	PACKAGE
VQ2001J	-30	2	-0.6	Plastic
VQ2001P	-30	2	-0.6	Side Braze

14-PIN DIP
SIDE BRAZE

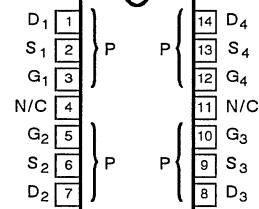


14-PIN PLASTIC



TOP VIEW

Dual-In-Line Package



Performance Curves: VPMH03 (See Section 7)

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	VQ2001J	VQ2001P	UNITS
Drain-Source Voltage	V _{DS}	-30	-30	V
Gate-Source Voltage	V _{GS}	± 30	± 20	
Continuous Drain Current	I _D	-0.6	-0.6	A
T _A = 100°C		-0.12	-0.12	
Pulsed Drain Current ¹	I _{DM}	± 2	± 2	W
Power Dissipation – Single	P _D	1.3	1.3	
T _A = 100°C		0.52	0.52	
Power Dissipation – Quad		2	2	
T _A = 100°C		0.8	0.8	
Operating Junction and Storage Temperature	T _j , T _{stg}	-55 to 150		°C
Lead Temperature (1/16" from case for 10 seconds)	T _L	300		

THERMAL RESISTANCE

THERMAL RESISTANCE	SYMBOL	VQ2001J	VQ2001P	UNITS
Junction-to-Ambient – Single	R _{thJA}	96.2	96.2	°C/W
Junction-to-Ambient – Quad		62.5	62.5	

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ¹			LIMITS			
PARAMETER	SYMBOL	TEST CONDITIONS	VQ2001		UNIT	
			TYP ²	MIN	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0 \text{ V}$, $I_D = -10 \mu\text{A}$	-55	-30		V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = -1 \text{ mA}$	-3.6	-2	-4.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}$ $V_{GS} = \pm 16 \text{ V}$	± 1		± 100	nA
		$T_J = 125^\circ\text{C}$	± 5		± 500	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30 \text{ V}$ $V_{GS} = 0 \text{ V}$	-0.0001		-10	μA
		$T_J = 125^\circ\text{C}$	-0.3		-500	
On-State Drain Current ³	$I_{D(\text{ON})}$	$V_{DS} = -10 \text{ V}$, $V_{GS} = -12 \text{ V}$	-1.6	-1.5		A
Drain-Source On-Resistance ³	$r_{DS(\text{ON})}$	$V_{GS} = -12 \text{ V}$ $I_D = -1 \text{ A}$	1.8		2	Ω
		$T_J = 125^\circ\text{C}$	3.1		3.6	
Forward Transconductance ³	g_{FS}	$V_{DS} = -10 \text{ V}$, $I_D = -0.5 \text{ A}$	290	200		mS
Common Source Output Conductance ³	g_{OS}	$V_{DS} = -7.5 \text{ V}$, $I_D = -0.05 \text{ A}$	800			μs
DYNAMIC						
Input Capacitance	C_{iss}	$V_{DS} = -15 \text{ V}$ $V_{GS} = 0 \text{ V}$ $f = 1 \text{ MHz}$	130		150	pF
Output Capacitance	C_{oss}		75		100	
Reverse Transfer Capacitance	C_{rss}		20		60	
SWITCHING						
Turn-On Time	t_{ON}	$V_{DD} = -15 \text{ V}$, $R_L = 23 \Omega$ $I_D = -0.6 \text{ A}$, $V_{GEN} = -10 \text{ V}$ $R_G = 25 \Omega$ (Switching time is essentially independent of operating temperature)	18		30	ns
Turn-Off Time	t_{OFF}		13		30	

- NOTES: 1. $T_A = 25^\circ\text{C}$ unless otherwise noted.
 2. For design aid only, not subject to production testing.
 3. Pulse test; $PW = 300 \mu\text{s}$, duty cycle $\leq 2\%$.